

<b>Notice of References Cited</b>	Application/Control No. 10/731,540	Applicant(s)/Patent Under Reexamination TIDWELL ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0202012	09-2006	Grano et al.	235/379
*	B	US-2004/0245330	12-2004	Swift et al.	235/379
*	C	US-2003/0212637	11-2003	Turner, Michael B.	705/45
*	D	US-2004/0247168	12-2004	Pintsov et al.	382/137
*	E	US-2005/0229010	10-2005	Monk et al.	713/186
*	F	US-2003/0153299	08-2003	Perfit et al.	455/410
*	G	US-2003/0088461	05-2003	CHRISTENSEN, SCOTT N.	705/14
*	H	US-2002/0154795	10-2002	Lee et al.	382/125
*	I	US-6,535,728	03-2003	Perfit et al.	455/410
*	J	US-2003/0056104	03-2003	Carr et al.	713/176
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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